SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. \ 252121US2S		SERIAL NO. 10/828,282				
LIST OF	255	SENOTO CITED DV AF		APPLICANT AME IN 10/020,202						
LISTOF	KErci	RENCES CITED BY AP	PLICANT	Keiichi KUSHIDA, et al.						
				FILING DATE		GROUP				
				April 21, 2004						
				U.S. PATENT DOCUMENTS						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB FILING DATE CLASS IF APPROPRIATE				
СВ	AA	6,295,617	09/25/2001	S. SONOBE						
	AB									
	AC									
	AD									
	AE			·						
	AF									
	AG									
	AH						· · · · · · · · · · · · · · · · · · ·			
	Al				1		-			
	AJ									
	AK									
	AL		†							
	AM				1					
	AN				1					
			FO	REIGN PATENT DOCUMENTS	<u></u>	<u></u>				
•		DOCUMENT NUMBER	DATE	COUNTRY		TRANS YES	SLATION NO			
СВ	AO	2001-351398	12/21/2001	JAPAN			х			
	AP									
	AQ									
	AR									
	AS									
	AT									
	AU		·							
·	AV									
r		OTHER RE	FERENCES (I	Including Author, Title, Date, Pertinent	Pages, et	ic.)	-			
СВ	AW	P. RAMANATHAN, et al., IEEE VLSI Test Symposium, pages 292-297, "ZERO COST TESTING OF CHECK BITS IN RAMS WITH ON-CHIP ECC", April 7-9, 1992								
	AX									
	AY									
	AZ				Addit	ional References	sheet(s) attached			
Examiner /Cynthia Britt/					Date Considered 01/07/2007					
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.										

Form PTO 1449 (Modified)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO.		SERIAL NO. New Application				
(11.00)				252121US2S						
				APPLICANT						
LIST OF	REFER	RENCES CITED BY AP	PLICANT	Keiichi KUSHIDA, et al.						
				FILING DATE Herewith		GROUP				
				U.S. PATENT DOCUMENTS						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS			FILING DATE APPROPRIATE		
	AA									
	AB									
	AC			·						
	AD									
	AE					·				
	AF									
	AG									
	АН									
	Al									
	AJ									
	AK									
	AL									
	AM									
	AN		'		<u> </u>					
			FC	REIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY		TRANS YES		LATION NO		
	AO			,						
	AP		·							
	AQ									
	AR									
	AS									
	AT		<u> </u>							
	AU									
	AV		<u> </u>	<u> </u>		<u></u>				
		OTHER RI	EFERENCES	(including Author, Title, Date, Pertinen	t Pages, e	tc.)				
CB Kiyohiro FURUTANI, et al., "A BUILT-IN HAMMING CODE ECC CIRCUIT FOR DRAM'S", IEEE Journal of Sci AW Circuits, Vol. 24, No. 1, February 1989, pgs. 50-56										
	AX									
	AY									
-	AZ				☐ Add	itional Refe	erences	sheet(s) attached		
Examiner	ner /Cynthia Britt/						Date Considered 01/07/2007			
*Examiner: Ir conformance	nitial if r	eference is considered, ot considered. Include c	whether or no	of citation is in conformance with MPEP 60 n with next communication to applicant.	09; Draw li	ne through				